INDEX

Journal of Quality Technology

Volume 24, Nos. 1–4, 1992

ARTICLES

All articles, including material that appears in the Computer Programs and Technical Aids Departments, are listed alphabetically by author and numbered sequentially. These numbers are used to identify the articles in the Key Words list, which begins on page 000.

1. BANKS, D. L. AND PARMIGIANI, G., *Pre-Analysis of Superlarge Industrial Data Sets* ..... July, 115–129
2. CROWDER, S. V. AND HAMILTON, M., *An EWMA for Monitoring a Process Standard Deviation* January, 12–21
3. DAUDIN, J. J., *Double Sampling $\bar{X}$ Charts* ..... April, 78–87
4. EBIBL, S.; KESS U.; AND PUKELSHEIM, F., *Quality Planning of Manufacturing Processes: Achieving a Target Value* ..... January, 22–26
5. FARNUM, N. R., *Control Charts for Short Runs: Nonconstant Process and Measurement* July, 138–144
6. FRANKLIN, L. A. AND WASSERMAN, G. S., *Bootstrap Lower Confidence Limits for Capability Indices* ..... October, 196–210
7. GAN, F. F. AND KOEHLER, K. J., *A Goodness-of-Fit Test Based on P-P Probability Plots* ..... April, 96–102
8. GUIRGUIS, G. H. AND RODRIGUEZ, R. N., *Computation of Owen's Q Function Applied to Process Capability Analysis* ..... October, 236–246
9. HAMADA, M., *An Explanation and Criticism of Minute Accumulating Analysis* ..... April, 70–77
10. HAMADA M., AND WU, C. F. J., *Analysis of Designed Experiments with Complex Aliasing* ..... July, 130–137
11. HAMILTON, M. D., *Average Run Lengths of Exponentially Weighted Moving Average Control Charts for Monitoring a Process Standard Deviation* ..... January, 44–50
12. HAWKINS, D. M., *A Fast Accurate Approximation for In-control and Out-of-control Average Run Lengths for Cusums* ..... January, 37–43
13. INMAN, J.; LEDOLTER, J.; LENTH, R. V.; AND NIEMI, L., *Two Case Studies Involving an Optical Emission Spectrometer* ..... January, 27–36
14. JOHNSON, T., *The Relationship of C_{pm} to Squared Error Loss* ..... October, 211–215
15. KALBFLEISCH, J. D. AND LAWLESS, J. F., *Some Useful Statistical Methods for Truncated Data* July, 145–152
16. KAMINSKY, F. C.; BENNEYAN, J. C.; AND DAVIS, R. D., *Statistical Control Charts Based on a Geometric Distribution* ..... April, 63–69
17. KUSHLER, R. H. AND HURLEY, P., *Confidence Bounds for Capability Indices* ..... October, 188–195
18. MCSHANE, L. M. AND TURNBULL, B. W., *New Performance Measures for Continuous Sampling Plans Applied to Finite Production Runs* ..... July, 153–161
19. MYERS, R. H.; VINING, G. G.; GIOVANNATTI-JENSEN, A.; AND MEYERS, S. L., *Variance Dispersion Properties of Second-Order Response Surface Designs* ..... January, 1–11
20. NELSON, L. S., *A Randomization Test for Ordered Alternatives* ..... January, 51–53
21. NELSON, L. S., *Sample Sizes for Two-Sample Tests on Means* ..... April, 103–108
22. NELSON, L. S., *Economic Balance of Sampling and Testing* ..... July, 162–164
23. NELSON, L. S., *Propagation of Error* ..... October, 232–235
24. PEARN, W. L.; KOTZ, S.; AND JOHNSON, N. L., *Distributional and Inferential Properties of Process Capability Indices* ..... October, 216–231
25. RODRIGUEZ, R. N., *Recent Developments in Process Capability Analysis* ..... October, 176–187
26. TRACY, N. D.; YOUNG, J. C.; AND MASON, R. L., *Multivariate Control Charts for Individual Observations* April, 88–95

DEPARTMENTS

Computer Programs

7. GAN, F. F. AND KOEHLER, K. J., *A Goodness-of-Fit Test Based on P-P Probability Plots* ..... April, 96–102
8. GUIRGUIS, G. H. AND RODRIGUEZ, R. N., *Computation of Owen's Q Function* ..... October, 236–246

10. HAMILTON, M. D., AND CROWDER, S. V. *Average Run Lengths of Exponentially Weighted Moving Average Control Charts for Monitoring a Process Standard Deviation* ..... January, 44–50
17. MCSHANE, L. M. AND TURNBULL, B. W., *New Performance Measures for Continuous Sampling Plans Applied to Finite Production Runs* ..... July, 153–161

Technical Aids

20. NELSON, L. S., *A Randomization Test for Ordered Alternatives* ..... January, 51–53
21. NELSON, L. S., *Sample Sizes for Two-Sample Tests on Means* ..... April, 103–108
22. NELSON, L. S., *Economic Balance of Sampling and Testing* ..... July, 162–164
23. NELSON, L. S., *Propagation of Error* ..... October, 232–235

Book Reviews

AFT, L., *Fundamentals of Industrial Quality Control* ..... B. GUNTER July, 166–168
CALVIN, T. W., *How and When to Perform Bayesian Acceptance Sampling* ..... W. E. THOMPSON July, 173
DOWDY S. AND WEARDEN, S., *Statistics for Research* ..... L. S. NELSON July, 168
FEIGENBAUM, A. V., *Total Quality Control* ..... L. S. NELSON January, 56–57
FELLERS, G., *SPC for Practitioners: Special Cases and Continuous Processes* ..... R. W. KULP April, 112–113
FREUND, R. J. AND LITTELL, R. C., *SAS System for Regression, Second Edition* ..... J. C. HULL January, 57–60
FREUND, R. J., LITTELL, R. C., AND SPECTOR, P. C., *SAS System for Linear Models, Third Edition* .... J. C. HULL January, 57–60
GRIEF, M., *The Visual Factory: Building Participation Through Shared Information* ... W. E. BREISCH January, 60–61
HAHN, G. J. AND MEEKER, W. Q., *Statistical Intervals: A Guide for Practitioners* .... W. M. BOWEN July, 170–172
ISHIKAWA, K., *Introduction to Quality Control* ..... H. V. ROBERTS January, 55–56
JOHN, P. W. M., *Statistical Methods in Engineering and Quality Assurance* ..... J. G. VOELKEL July, 165–166
KECECIOLU, D., *Reliability Engineering Handbook* ..... A. DAVIS July, 169–170
KIRISHNAIAH, P. R. AND RAO, C. R., (eds.), *Handbook of Statistics 7* ..... H. OHTA July, 172–173
LEVINE, G. A., *A Guide to SPSS for Analysis of Variance* ..... J. N. KENNEDY January, 54–55
LOCHNER, R. H. AND MATAR, J. E., *Designing for Quality* ..... L. B. HARE April, 110–111
SHINA, S. G., *Concurrent Engineering and Design for Manufacture of Electronic Products* .. M. PECHT April, 111
TAYLOR, J. K., *Statistical Techniques for Data Analysis* ..... L. S. NELSON July, 168–169
TIERNEY, L., *LISP-STAT: An Object-Oriented Environment for Statistical Computing and Dynamic Graphics* ..... R. L. EDGEMAN April, 111–112
TUFTE, E. R., *Envisioning Information* ..... K. MILLER January, 61
WALTERS, F. H., *Sequential Simplex Optimaization* ..... L. S. NELSON July, 164–165
WETHERILL, G. B. AND BROWN, D. W., *Statistical Process Control: Theory and Practice* .. J. S. DOWD April, 109–110
WILSON, E. B., JR., *An Introduction to Scientific Research* ..... R. L. PERRY April, 113

Book Reviewers

Breisch, W. E. ..... January, 60–61
Bowen, W. M. ..... July, 170–172
Davis, A. ..... July, 169–170
Dowd, J. S. ..... April, 109–110
Edgeman, R. L. ..... April, 111–112
Gunter, B. ..... July, 166–168
Hare, L. B. ..... April, 110–111
Hull, J. C. ..... January, 57–60
Kennedy, J. N. ..... January 54–55
Kulp, R. W. ..... April, 112–113
Miller, K. ..... January 61
Nelson, L. S. ..... January, 56–57
Nelson, L. S. ..... July, 164–165
Nelson, L. S. ..... July, 168
Nelson, L. S. ..... July, 168–169
Ohta, H. ..... July, 172–173
Pecht, M. ..... April, 111
Perry, R. L. ..... April, 113
Roberts, H. V. ..... January, 55–56
Thompson, W. E. ..... July, 173
Voelkel, J. G. ..... July, 165–166

MISCELLANEOUS

Corrigenda ..... October, 251
Editorial ..... October, 175
Editorial Collaborators ..... October, 250

KEY WORDS

The numbers used with the key words are the numbers assigned to the articles listed on the previous pages. They are not page numbers.

Acceptance Sampling by Attributes, 9, 18
Accumulation Analysis, 9
Amalgamation, 20
Approximation, 12
Average Run Length, 3, 12
Attribute Control Charts, 16
Bivariate Noncentral t Distribution, 8
Bootstrap Estimates, 6
Bootstrap Methods, 25
Capability Indices, 6, 8, 14, 17, 24, 25
Censored Data, 9
Confidence Limits, 6, 8, 17, 25
Continuous Sampling, 18
Control Charts, 5
Count Data, 16
Cumulative Sum Control Chart, 3, 12
Data Analysis, 1
Design Efficiencies, 19
Design of Experiments, 4
Deviations from Nominal Value, 5
Discrete Data, 16
D-Optimality, 19
Double Sampling, 3
EWMA Chart, 3
Exponential Distribution, 7
Expected Values, 24
Factorial Experiments, 13
Fast Initial Response, 12
Field Reliability, 15
Geometric Distribution, 16
Goodness-of-Fit Methods, 25
G-Optimality, 19
Graphics, 1
Graphical Methods, 25
Grouped Data, 9
Gumbel Distribution, 7
Hypothesis Testing, 20
Imputation, 1
Integral Equation, 2
Interactions, 10
Kernel Density Estimates, 25
Lifetime Data, 15
Location Parameter, 2
Log-Gamma Distribution, 2
Loss Functions, 14, 24
Measurement Error, 22
Measurement Systems, 13
MIL-STD-1235B, 18
Minimum Cost Sampling Plans, 22
Miss Rates, 17
Mixed-Level Design, 10
Multivariate Capability Indices, 24
Multivariate Quality Control, 26
Multivariate Time Series, 1
Negative Binomial Distribution, 16
Nonparametric Estimation, 15
Nonparametric Tests, 20, 21
Normal Distribution, 7
Normal Distribution Tail Areas, 8
Ordered Alternatives, 20
Outgoing Quality, 18
Partial Aliasing, 10
Plackett-Burman Design, 10
Prediction, 4
Prediction Limits, 18
Probability Limits, 18
Process Capability Analysis, 8, 25
Randomization Tests, 20, 21
Rank Sum Tests, 21
Reliability, 9
Response Surface Methodology, 4, 19
Sampling, 22
Sample Size, 21
Scale Parameter, 2
Screening Experiments, 10
Sequential Experimentation, 4
Shapiro-Francia Statistic, 7
Shapiro-Wilk Statistic, 7
Shewhart Control Chart, 3
Significance Tests, 20
Spectrometry, 13
Split-Plot Design, 9
Statistical Process Control, 3, 16
Student's t, 21
T^2 Control Charts, 26
Tolerance Limits, 18
Truncated Data, 15
Two-Sample Tests, 21
Unbiasedness, 24
Variances, 24
Variance Components, 13
VSI Control Chart, 3
Warranty Data, 15